

Internal Assesment Test - II

Solutions


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module scaled_square ( output reg signed [7:-12] y,<br>input signed [7:-12] c in, x,
                             signed [7:-12] c_in, x,
                    input [11:0] i,
                    input start,
                   input clk, reset );
     wire c_ram_wr;
     reg c_ram_en, x_ce, mult_sel, y_ce;
      reg signed [7:-12] c_out, x_out;
      reg signed [7:-12] c_RAM [0:4095];
     reg signed [7:-12] operand1, operand2;
     parameter [1:0] step1 = 2'b00, step2 = 2'b01, step3 = 2'b10;
      reg [1:0] current_state, next_state;
     assign c_ram_wr = 1^{\prime}b0;
    always @(posedge clk) // c RAM - flow through
       if (c_ram_en)
         if (c_ram_wr) begin
         c_RAM[i] \leq c_in;
         c_ out \leq c_ in;
         end
         else
         c_out \leq c_RAM[i];
      always @(posedge clk) // y register
       if (y_ce) begin
         if (!mult_sel) begin
         operand1 = c_out;operand2 = x_out; end
         else begin
         operand1 = x out;
         operand2 = y;
         end
        y \le operand1 * operand2;
        end
                                                                                                            5 Marks
3 Error-Correcting Codes (ECC)
        ■ Allow identification of the flipped bit
        ■ Hamming Codes
                E.g., for single-bit-error correction of N-bit word, need log_2N + 1 extra bits
        Example: 8-bit word, d_1... d_8\blacksquare12-bit ECC code, e_1...e_{12}e1, e2, e4, e8 are check bits, the rest data
                                                            d_{1}d<sub>2</sub>d_{3}d_{\overline{4}}d_{\overline{5}}d<sub>6</sub>d_{7}d_8e_{1}e_{2}e3
                                                            e_4e<sub>5</sub>e<sub>6</sub>e<sub>7</sub>e_{8}e9
            e_{11} e_{10}e_{12}4Marks
```


only 256 bytes of data memory and 4K to 16K bytes of instruction memory on the chip. The chip has two 8-bit input/output ports, P0 and P2, as well as a number of control signals that can be used to connect to external memory. Figure shows how they would be used to connect to an external 128K x 8-bit asynchronous SRAM, in which the lower 64K locations are used for instructions and the upper 64K locations for data. P2 provides the most significant address byte, and P0 is multiplexed with the least significant address byte and instruction and data bytes. Since information transfer on P0 is bidirectional, tristate drivers are used internally in the microcontroller and in the memory data pins.

The 8051 activates the address-latch enable (ALE) signal when it drives the least significant address bits on P0. We provide an 8-bit latch to hold these bits for the remainder of the memory access cycle. During an instruction read access, the 8051 activates the program-store enable (!PSEN) signal, driving it to a low logic level. At other times, including data accesses, the signal is at a high logic level. Hence, we can use this signal directly as the most significant address bit to distinguish between instruction and data accesses to the external memory. The 8051 activates the RD signal during data read accesses and the (!WR) signal during data write accesses. We use !WR directly to control the memory's write enable (!WE) signal. However, we need a small amount of glue logic to derive the chip enable (!CE) and output enable (!OE) signals.